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CCS L 97

SJ

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Semiconductor equipment - Testing methods for chemical
vapor deposition (CVD) equipment used in integrated circuit
manufacturing**

(English Translation)

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Table of Contents

What this standard covers	1
Document data	2

What this standard covers

This standard specifies the testing methods for chemical vapor deposition (CVD) equipment used in integrated circuit manufacturing. This standard is applicable to the testing of CVD equipment used in integrated circuit manufacturing at the stages of technology development, factory testing, client verification, and third-party testing. CVD equipment or other stages of testing used in other semiconductor product manufacturing can be used as a reference.

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